

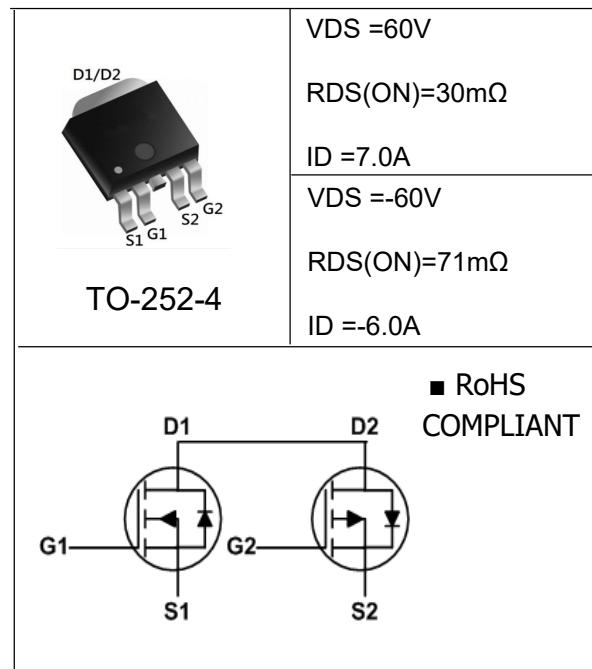
**60V N-Channel MOSFET  
-60V P-Channel MOSFET**

### ●General Description

The N-ch and P-ch MOSFET LH4559A has the low RDS(on),low gate charge,fast switching and excellent avalanche characteristics.This device is suitable for fast charge and lighting.

### ●Features

- Green Device Available
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- Advanced high cell density Tren ch technology



### ●Ordering Information:

Part number	LH4559A		
Package	TO252-4		
Basic ordering unit (pcs)	2500		
Normal Package Material Ordering Code	LH4559AT7-TO252-4-TAP		
Halogen Free Ordering Code	LH4559AT7-TO252-4-TAP-HF		

### ●Absolute Maximum Ratings (TC =25°C)

<b>PARAMETER</b>	<b>SYMBOL</b>	<b>Value</b>		<b>UNIT</b>
		<b>N-ch</b>	<b>P-ch</b>	
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	60	-60	V
Gate-Source Voltage	V <sub>GS</sub>	±20	±20	V
Continuous Drain Current	I <sub>D</sub> @TA=25°C	7.0	-6.0	A
	I <sub>D</sub> @TA=100°C	5.5	-4.5	
Pulsed drain current	I <sub>DM</sub>	11	-8.5	A
Avalanche Energy	E <sub>AS</sub>	25.5	35.3	mJ
Avalanche Current	I <sub>AS</sub>	22.6	-26.6	W
Power Dissipation @TA=25°C	P <sub>D</sub>	1.5	1.5	
Operating Temperature	T <sub>J</sub>	-55~+150	-55~+150	°C
Storage Temperature	T <sub>STG</sub>	-55~+150	-55~+150	°C

**•N-Channel Electronic Characteristics**

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	60	--	--	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = 250\mu A$	1.2	--	2.5	V
Drain-source On Resistance <sup>2</sup>	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 4A$		30	35	$m\Omega$
		$V_{GS} = 4.5V, I_D = 2A$	--	37	43	
Drain-Source Leakage Current	$I_{DSS}$	$V_{DS} = 48V, V_{GS} = 0V, T_J = 25^\circ C$	--	--	1	$\mu A$
		$V_{DS} = 48V, V_{GS} = 0V, T_J = 55^\circ C$	--	--	5	
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$	--	--	$\pm 100$	nA
Forward Transconductance	$g_{fs}$	$V_{DS} = 5V, I_D = 4A$	--	21	--	S
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 15V, f = 1.0MHz$	--	1378	--	$pF$
Output Capacitance	$C_{oss}$		--	86	--	
Reverse Transfer Capacitance	$C_{rss}$		--	64	--	ns
Gate Resistance	$R_g$	$V_{DS} = 0V, V_{GS} = 0V, f = 1MHz$	--	3.2	--	$\Omega$
Total Gate Charge (10V)	$Q_g$	$V_{DS} = 48V, V_{GS} = 4.5V, I_D = 4A$	--	12.6	--	$nC$
Gate-Source Charge	$Q_{gs}$		--	3.2	--	
Gate-Drain Charge	$Q_{gd}$		--	6.3	--	
Turn-On Delay Time	$T_{d(on)}$	$V_{DD} = 30V, V_{GS} = 10V, RG = 3.3\Omega, ID = 14A$	--	8	--	$nS$
Rise Time	$T_r$		--	14.2	--	
Turn-Off Delay Time	$T_{d(off)}$		--	24.4	--	
Fall Time	$T_f$		--	4.6	7.0	
Continuous Source Current <sup>1,5</sup>	$I_S$	VG=VD=0V, Force Current	--	--	70	A
Pulsed Source Current <sup>2,5</sup>	$I_{SD}$		--	--	12	
Diode Forward Voltage <sup>2</sup>	$V_{SD}$	$V_{GS} = 0V, I_S = 1A, T_J = 25^\circ C$	--	--	1.2	V

Notes:

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
2. The data tested by pulsed, pulse width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$
3. The EAS data shows Max. rating. The test condition is  $V_{DD} = 25V, V_{GS} = 10V, L = 0.1mH, I_{AS} = 22.6A$
4. The power dissipation is limited by  $150^\circ C$  junction temperature
5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.

**•P-Channel Electronic Characteristics**

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0V, I_D = -250\mu A$	-60	--	--	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = -250\mu A$	-1.2	--	-2.5	V
Drain-source On Resistance <sup>2</sup>	$R_{DS(ON)}$	$V_{GS} = -10V, I_D = 4A$		71	87	$m\Omega$
		$V_{GS} = -4.5V, I_D = 2A$	--	90	120	
Drain-Source Leakage Current	$I_{DSS}$	$V_{DS} = -48V, V_{GS} = 0V, T_J = 25^\circ C$	--	--	1	$\mu A$
		$V_{DS} = -48V, V_{GS} = 0V, T_J = 55^\circ C$	--	--	5	
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$	--	--	$\pm 100$	nA
Forward Transconductance	$g_{fs}$	$V_{DS} = -5V, I_D = 3A$	--	15	--	S
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = -15V, f = 1.0MHz$	--	1447	--	$pF$
Output Capacitance	$C_{oss}$		--	97.3	--	
Reverse Transfer Capacitance	$C_{rss}$		--	70	--	ns
Gate Resistance	$R_g$	$V_{DS} = 0V, V_{GS} = 0V, f = 1MHz$	--	13.5	--	$\Omega$
Total Gate Charge (10V)	$Q_g$	$V_{DS} = -48V, V_{GS} = -4.5V, I_D = -3A$	--	9.86	--	$nC$
Gate-Source Charge	$Q_{gs}$		--	3.1	--	
Gate-Drain Charge	$Q_{gd}$		--	2.95	--	
Turn-On Delay Time	$T_{d(on)}$	$V_{DD} = -15V, V_{GS} = -10V, R_G = 3.3\Omega, I_D = -1A$	--	28.8	--	$nS$
Rise Time	$T_r$		--	19.8	--	
Turn-Off Delay Time	$T_{d(off)}$		--	60.8	--	
Fall Time	$T_f$		--	7.2	7.0	
Continuous Source Current <sup>1,5</sup>	$I_S$	$VG = VD = 0V, Force Current$	--	--	-6.0	$A$
Pulsed Source Current <sup>2,5</sup>	$I_{SD}$		--	--	-11	
Diode Forward Voltage <sup>2</sup>	$V_{SD}$	$V_{GS} = 0V, I_S = -1A, T_J = 25^\circ C$	--	--	-1.2	V

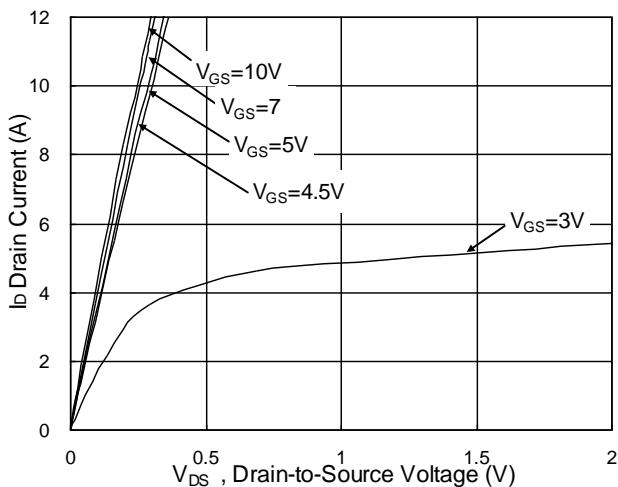
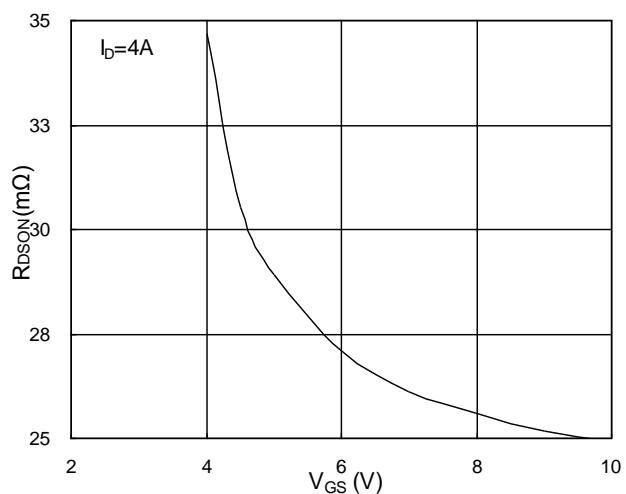
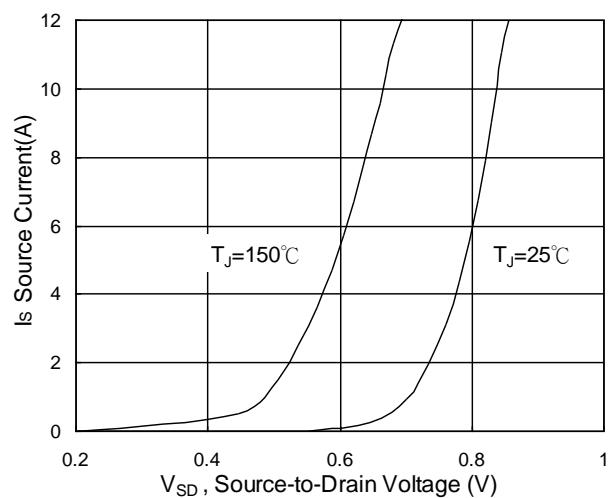
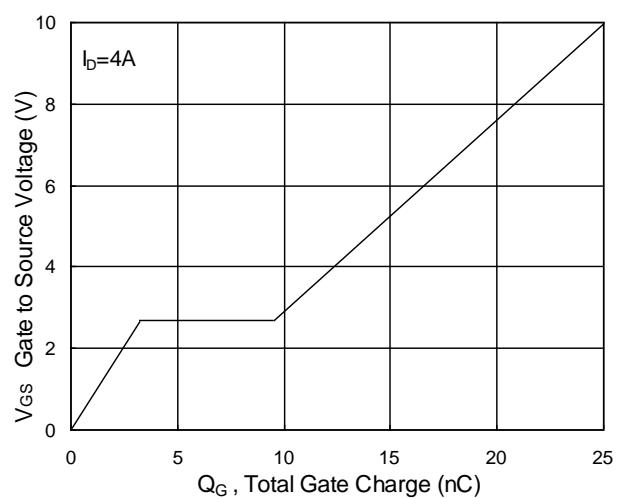
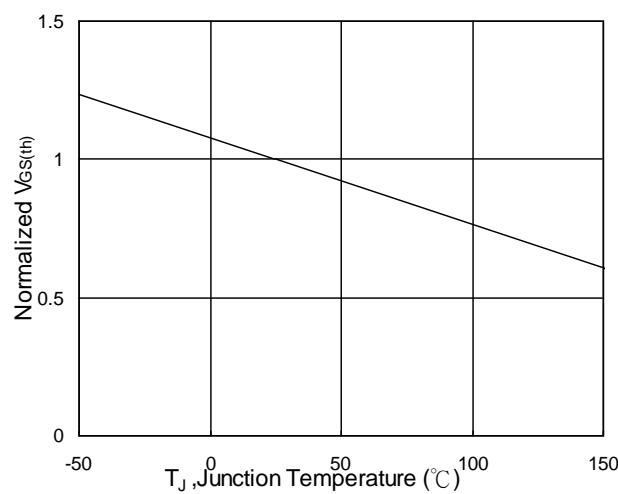
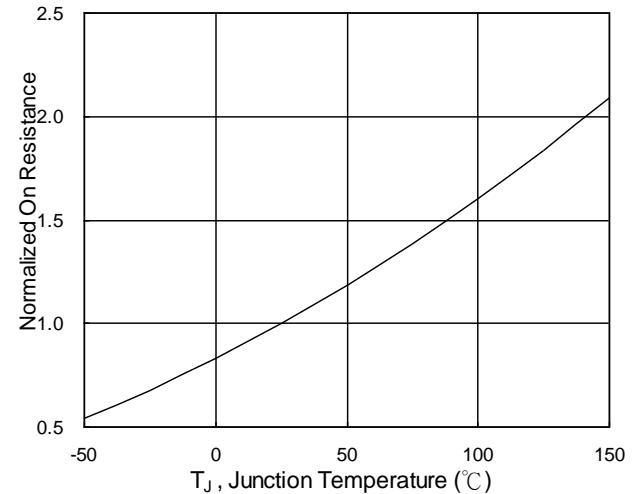
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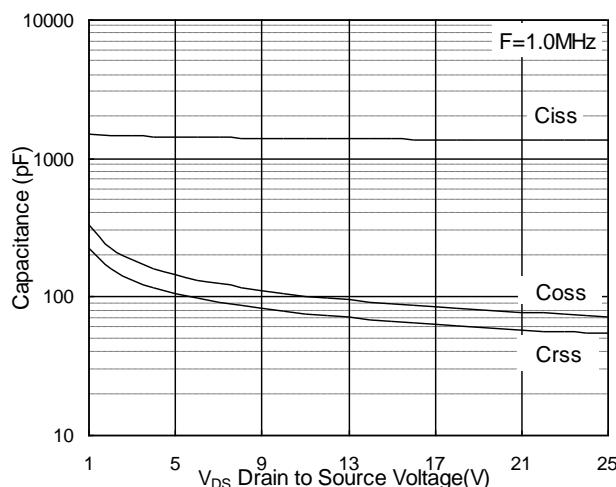
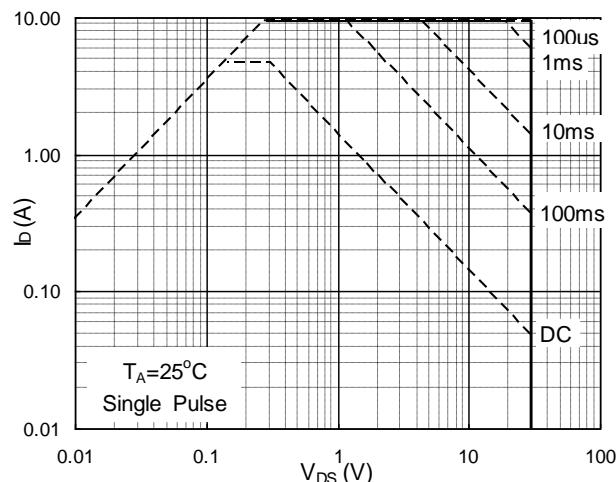
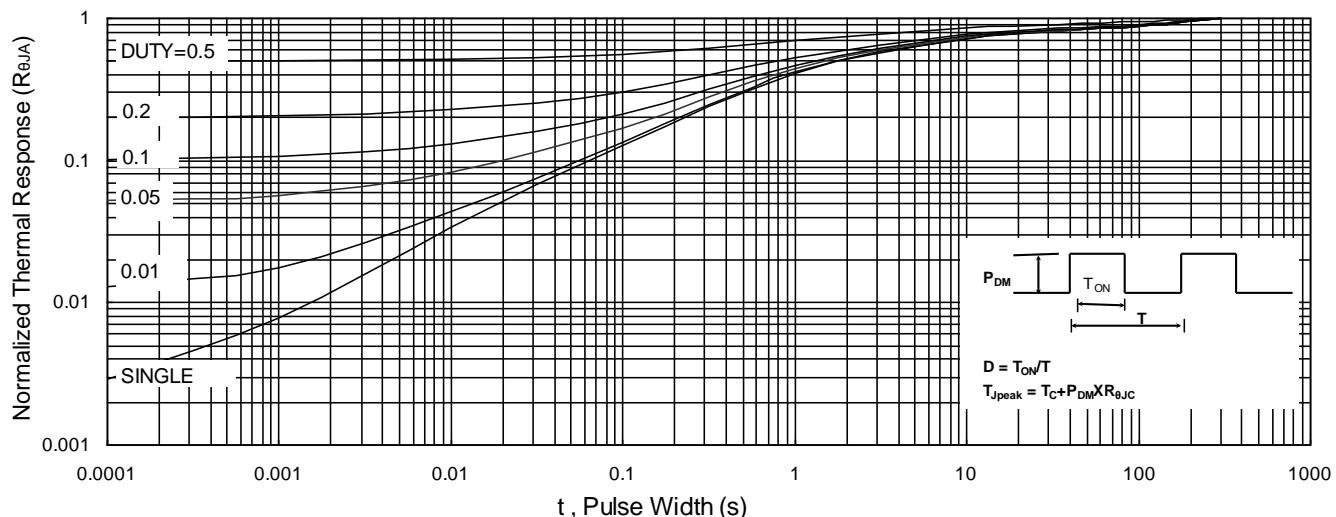
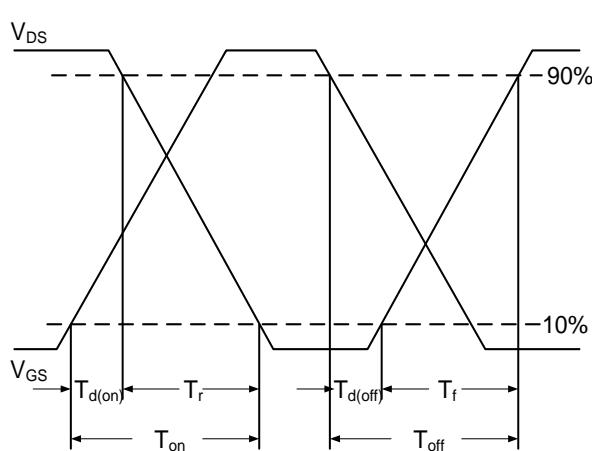
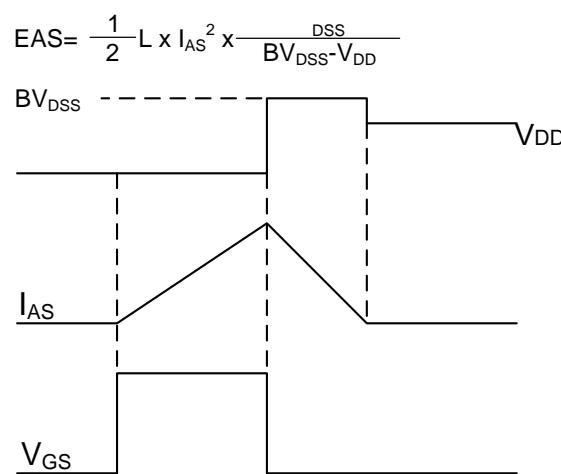
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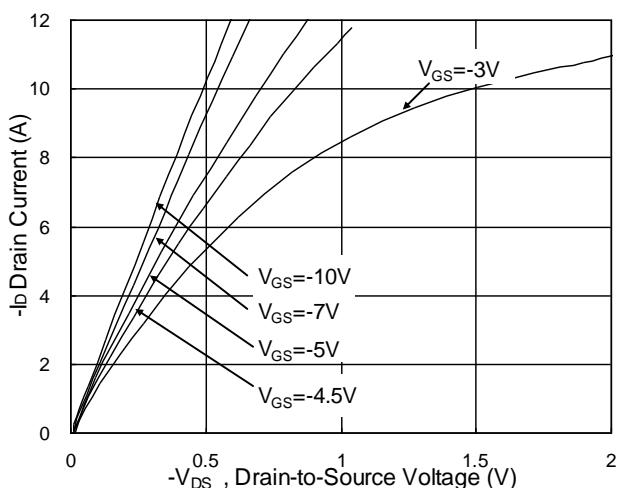
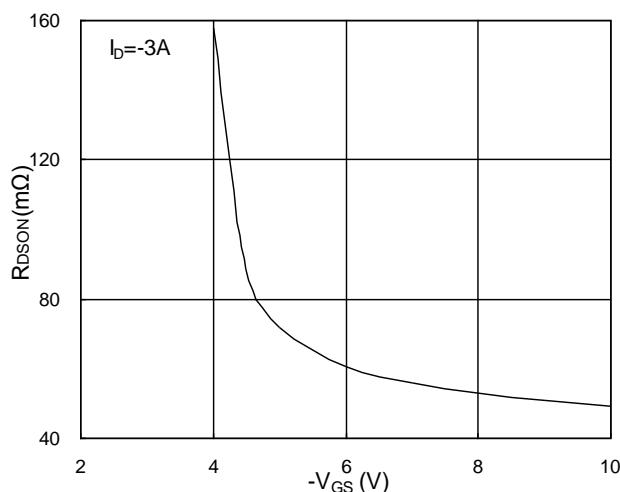
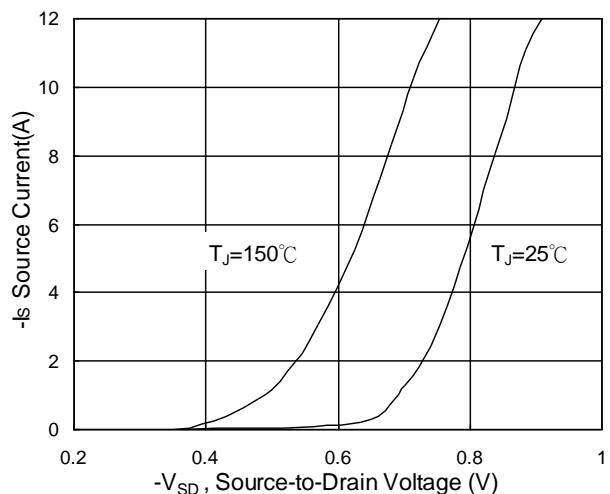
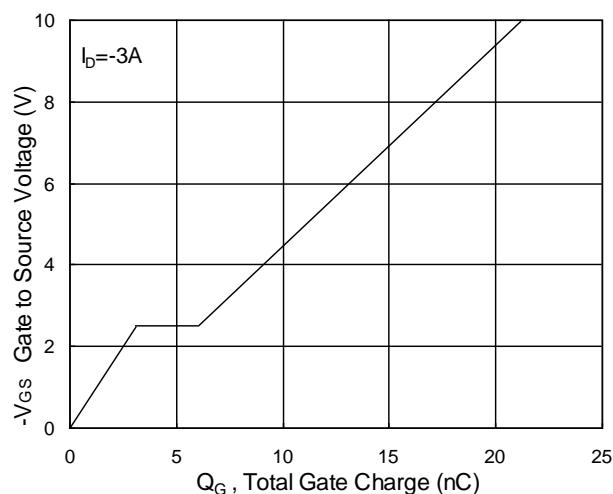
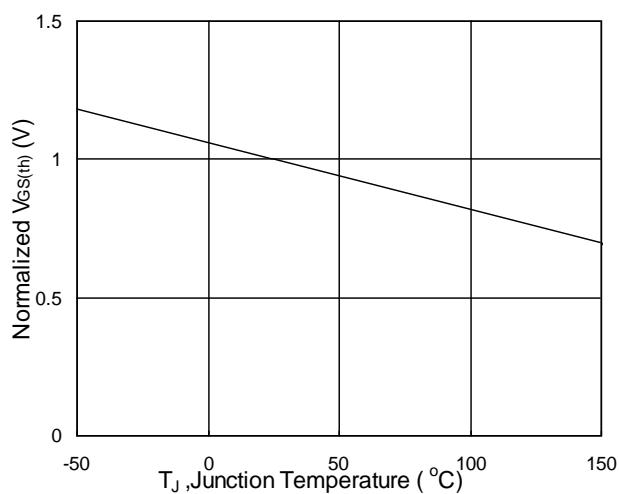
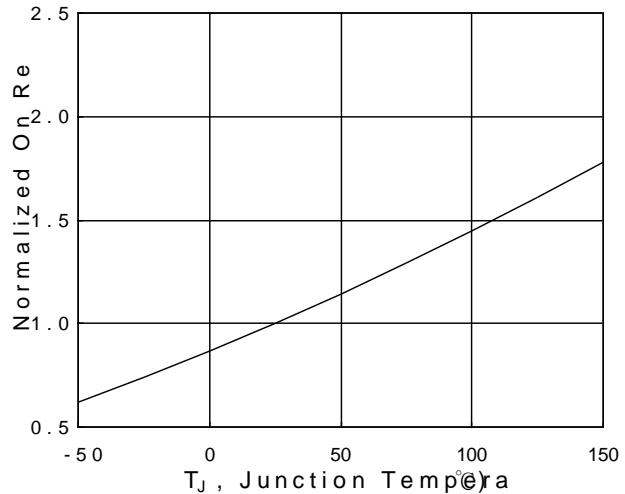
60V N-Channel MOSFET  
-60V P-Channel MOSFET

•Thermal Characteristics

PARAMETER	SYMBOL	MAX	UNIT
		SOP-8	
Thermal Resistance Junction-case <sup>1</sup>	R <sub>thJC</sub>	36	°C/W
Thermal Resistance Junction-ambient <sup>1</sup>	R <sub>thJA</sub>	85	°C/W

**●N-Channel Typical Characteristics**

**Fig.1 Typical Output Characteristics**

**Fig.2 On-Resistance v.s Gate-Source**

**Fig.3 Forward Characteristics of Reverse**

**Fig.4 Gate-Charge Characteristics**

**Fig.5 Normalized  $V_{GS(th)}$  v.s  $T_J$** 

**Fig.6 Normalized  $R_{DS(on)}$  v.s  $T_J$**

**•N-Channel Typical Characteristics (cont.)**

**Fig.7 Capacitance**

**Fig.8 Safe Operating Area**

**Fig.9 Normalized Maximum Transient Thermal Impedance**

**Fig.10 Switching Time Waveform**

**Fig.11 Unclamped Inductive Waveform**

**60V N-Channel MOSFET  
-60V P-Channel MOSFET**
**•P-Channel Typical Characteristics (cont.)**

**Fig.1 Typical Output Characteristics**

**Fig.2 On-Resistance v.s Gate-Source**

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**Fig.4 Gate-Charge Characteristics**

**Fig.5 Normalized  $V_{GS(th)}$  v.s  $T_J$** 

**Fig.6 Normalized  $R_{DS(on)}$  v.s  $T_J$**

**60V N-Channel MOSFET  
-60V P-Channel MOSFET**

•P-Channel Typical Characteristics (cont.)

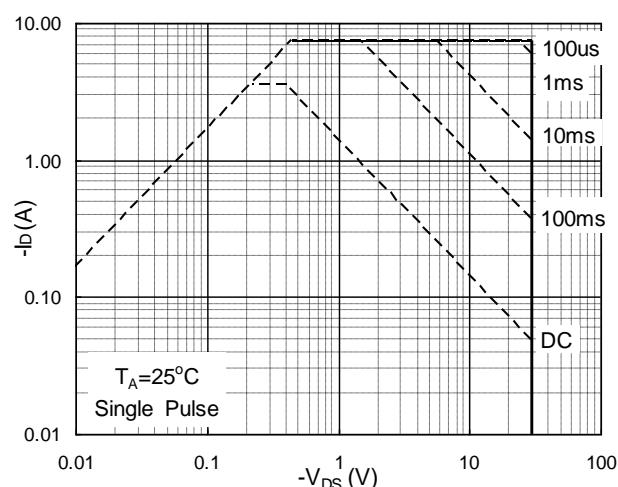
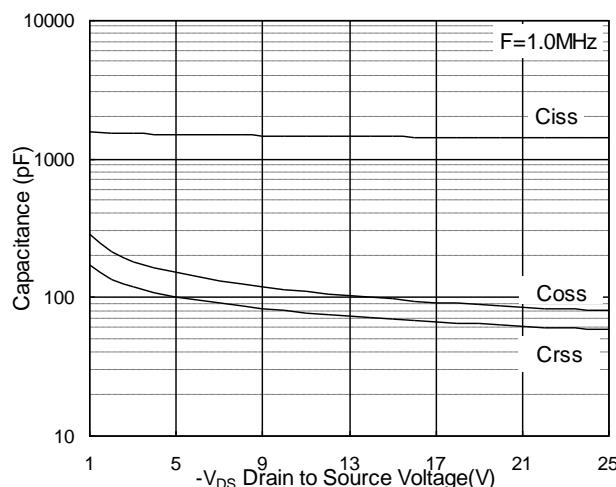


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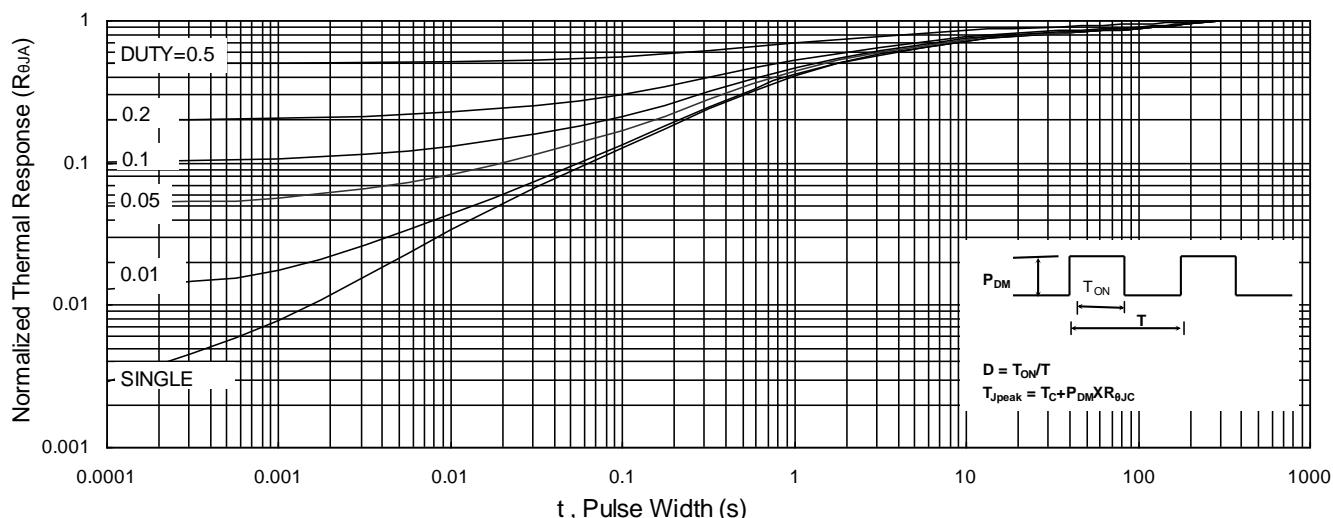


Fig.9 Normalized Maximum Transient Thermal Impedance

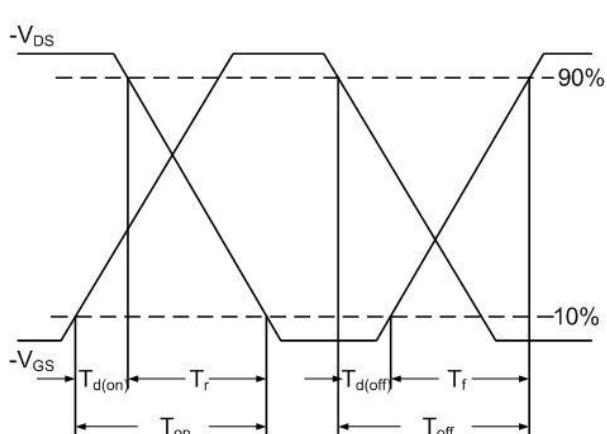


Fig.10 Switching Time Waveform

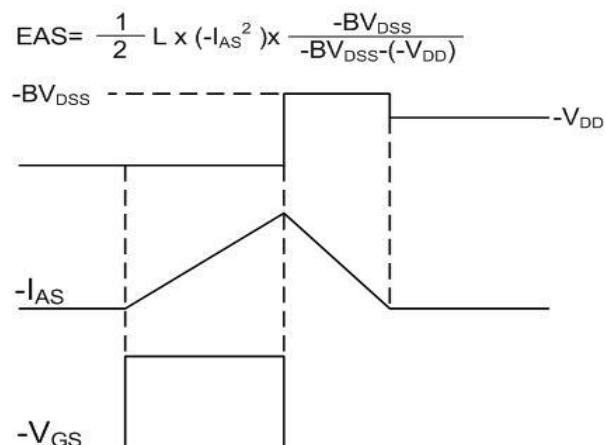


Fig.11 Unclamped Inductive Waveform